

**Search Notes**

Application/Control No.

10/773,629

Examiner

JOHN J. LEE

Applicant(s)/Patent under  
Reexamination

KRISHNAN ET AL.

Art Unit

2618

**SEARCHED**

Class	Subclass	Date	Examiner
455	522,126 69,525 67.11-13 134,70	9/23/2008	J.L
455	135,127.1	9/23/2008	J.L
455	115.1	9/23/2008	J.L
370	320,332	9/23/2008	J.L

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
455	522,69	9/26/2008	J.L
455	126,70	9/26/2008	J.L
455	67.11-13	9/26/2008	J.L
Interference and Inventor search		9/26/2008	J.L

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	9/23/2008	J.L
Nguyen Vo, Kincard Lester, and Duc Nguyen	3/23/2008	J.L